

## Specific-Fault Oriented Test Generation

- Three Approaches
- Internal Line Values Assigned ( D Algorithm) (Roth-1966)
- D-cubes
- Bridging faults
- Logic gate function change faults
- Input Values Assigned (PODEM) (Goel - 1981)
- X-Path-Check

Path propagation constraints to limit ATPG search space

- Backtracing
- Input and Internal Values Assigned (FAN) (Fujiwara)
- Efficiently constrained backtarce


## Fault Cone and D-frontier

- Fault Cone
- Set of hardware affected by fault
- D-frontier
- Set of gates closest to POs with fault effect(s) at input(s)




## D-Algorithm -- Roth IBM (1966)

- Fundamental concepts invented:
- First complete ATPG algorithm
- D-Cube
- D-Calculus
- Implications - forward and backward
- Implication stack
- Backtrack
- Test Search Space



## D Algorithm

- Example
- Test for Stuck-at-0 on Lower Input to Gate B
- Implication
- Record Effects of Previous Assignments




## D Algorithm

- Propagation
- Assign Required Gate Input Values
- Os on other inputs of OR, NOR Gates with D or $\bar{D}$ Input
- 1s on other inputs of AND, NAND Gates with D or $\bar{D}$ Input



## Line Justification

- Find Input Assignment to Place Value v on Line g
- Path Tracing Approach
- Propagate Signals using Element Functions
- Must Choose Element Input Values and Paths
- Primitive cube of an element (gate) with output Z
- List of prime implicants of $Z$ and $Z^{\prime}$

| AND |
| :--- |
| A B Z <br> 1 1 1 <br> 0 - 0 <br> - 0 0 |

NAND

| A | B | Z |
| :---: | :---: | :---: |
| 1 | 1 | 0 |
| 0 | - | 1 |
| - | 0 | 1 |$\quad$| Implication (no choices) |
| :--- |

## D Algorithm

- Line Justification
- Assign Required Gate Input Values
- 0 on lower input of $C$ to give 0 on output




## D Algorithm

- Example
- Test for Stuck-at-1 on Gate A Output
- Activate Fault
- Put 0 on Faulty Lead



## D Algorithm

- Example
- Test for Stuck-at-1 on Gate A Output
- Implication
- Record Effects of Previous Assignments



## D Algorithm

- Example
- Test for Stuck-at-1 on Gate A Output
- Propagation
- Select Path to Propagate D to Output




## D Algorithm

- Example
- Test for Stuck-at-1 on Gate A Output
- Implication
- Record Effects of Previous Assignments




## D Algorithm

- Example
- Test for Stuck-at-1 on Gate A Output
- Implication
- Record Effects of Previous Assignments
- Test is $\mathrm{U}, \mathrm{V}, \mathrm{Y}, \mathrm{Z}=0,0,0,1$




## Singular Cover

- Singular Cover
- Minimal set of input signal assignments to show essential prime implicants of Karnaugh map


| Gate |  |  |  | Inputs | Output | Gate |  |  | Inputs |  |  |  | Output |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| AND | $A$ | $B$ | $d$ | NOR | $d$ | $e$ | $F$ |  |  |  |  |  |  |
| 1 | 0 | $X$ | 0 | 1 | 1 | X | 0 |  |  |  |  |  |  |
| 2 | $X$ | 0 | 0 | 2 | $X$ | 1 | 0 |  |  |  |  |  |  |
| 3 | 1 | 1 | 1 | 3 | 0 | 0 | 1 |  |  |  |  |  |  |



## Testing Digital Systems I

## D Algorithm

- D Intersection
- Defines how different D-cubes can coexist for different gates in logic circuit
- If one cube assigns a specific signal value, the other cubes must assign either that same value or X
- $1 \cap 1=1 \cap X=X \cap 1=1$
- $0 \cap 0=0 \cap X=X \cap 0=0$
- $X \cap X=X$
$\psi, \phi$ represent incompatible assignments
$\mu, \lambda$ represent incompatibility if both present

| $\cap$ | 0 | 1 | X | D | $\overline{\mathrm{D}}$ |
| :--- | :--- | :--- | :--- | :--- | :--- |
| $\mathbf{0}$ | 0 | $\phi$ | 0 | $\psi$ | $\psi$ |
| $\mathbf{1}$ | $\phi$ | 1 | 1 | $\psi$ | $\psi$ |
| X | 0 | 1 | X | D | D |
| D | $\psi$ | $\psi$ | D | $\mu$ | $\lambda$ |
| D | $\psi$ | $\psi$ | D | $\lambda$ | $\mu$ |

## D Algorithm

- Primitive D-cube of Failure (PDF)
- Models fault including
- SA1: represented by $\bar{D}$
- SAO: represented by D
- Example: AND gate
- PDF for output SAO is 11 D
- PDFs for output SA1 are $0 \times \overline{\mathrm{D}}, \times 0 \overline{\mathrm{D}}$
- Propagation D-cube
- Models conditions under which fault effect propagates through gate


## Implication Procedure

1. Model fault with appropriate PDF
2. Select propagation D-cubes to propagate fault effect to a PO (D-drive procedure)
3. Select singular cover cubes to justify internal circuit signals (Consistency procedure)

- D Algorithm's main problem
- Selects cubes and singular covers arbitrarily


